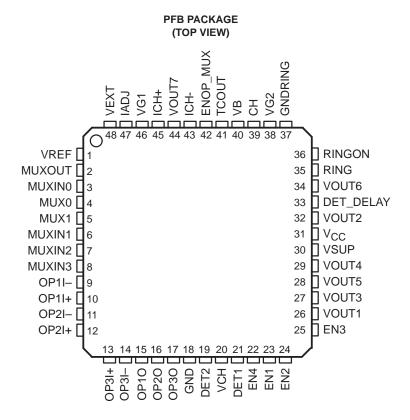
- Li-Ion Battery Charging Control
- Over-Voltage Shutdown
- Seven Low-Dropout Low-Noise Linear Voltage Regulators (LDO)
- Voltage Detectors (With Power-Off Delay)
- Four-Channel Analog Multiplexer

- Three General-Purpose Operational Amplifiers
- Ringer Driver
- Power Supply Switch for Accessories
- Low Quiescent Current
- 48-pin TQFP



description

The TWL2203 incorporates a complete power-management system for a cellular telephone that uses lithium-ion cells. The device includes circuitry to control the gate voltage of two P-channel MOSFETs. The MOSFETs perform constant-voltage/constant-current charging (CVCC). The TWL2203 has seven low-drop linear voltage regulators (LDO) to regulate the battery power supply to the different sections of the phone, a battery voltage monitor, a ringer driver, an analog multiplexer, and three general-purpose operational amplifiers for signal conditioning.

The TWL2203 is packaged in TI's 48-pin thin-quad flat package (PFB).



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

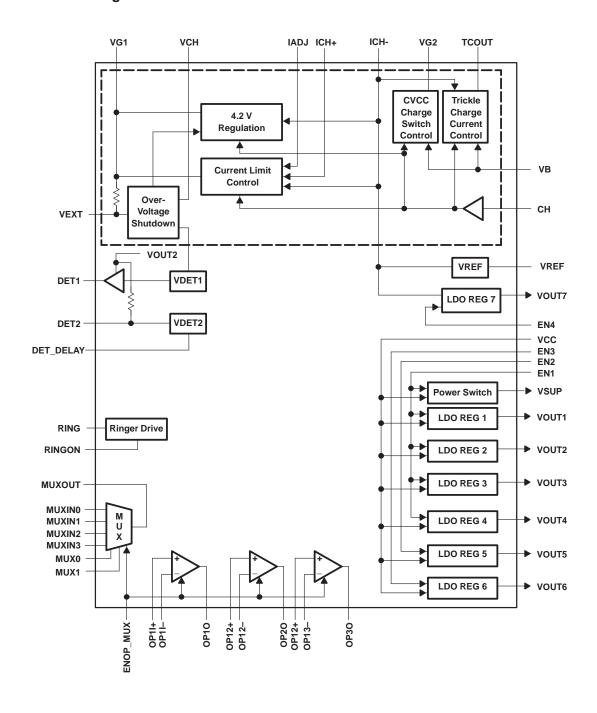
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AVAILABLE OPTIONS

	PACKAGE
TA	PLASTIC THIN-QUAD FLAT PACKAGE (PFB)
-30°C to 85°C	TWL2203PFB

functional block diagram



Terminal Functions

TERMINAL						
NO.		1/0	DESCRIPTION			
NAME	QFB					
СН	39	ı	CMOS signal input set to logic high to enable battery-charging function			
DET_DELAY	33	I/O	Delay programming pin for VDET2			
DET1	21	0	Voltage detector CMOS output			
DET2	19	0	Voltage detector output with 40-kΩ pull–up resistor			
EN1	23	ı	Set to logic high to enable LDO regulators 1–4 and power supply switch			
EN2	24	ı	Set to logic high to enable LDO regulator 5			
EN3	25	ı	Set to logic high to enable LDO regulator 6			
EN4	22	ı	Set to logic high to enable LDO regulator 7			
ENOP_MUX	42	Ι	Set to logic high to enable the op amps and the analog multiplexer			
GND	18		Ground for most sections of the device			
GNDRING	37		Ringer ground			
IADJ	47	I/O	Terminal for gain control of battery-charging current monitor			
ICH-	43	ı	Current-sense input/trickle charge, input/power supply to LDO regulator 7, and reference.			
ICH+	45	Ι	Current-sense input			
MUX0	4	Ι	Analog multiplexer channel selector bit-input (logic high is true)			
MUX1	5	ı	Analog multiplexer channel selector bit-input (logic high is true)			
MUXIN0	3	ı	Analog multiplexer input 0			
MUXIN1	6	ı	Analog multiplexer input 1			
MUXIN2	7	ı	Analog multiplexer input 2			
MUXIN3	8	ı	Analog multiplexer input 3			
MUXOUT	2	0	Analog multiplexer output			
OP1I-	9	I	Op amp 1 negative input			
OP1I+	10	I	Op amp 1 positive input			
OP1O	15	0	Op amp 1 output			
OP2I-	11	I	Op amp 2 negative input			
OP2I+	12	Ι	Op amp 2 positive input			
OP2O	16	0	Op amp 2 output			
OP3I-	14	I	Op amp 3 negative input			
OP3I+	13	I	Op amp 3 positive input			
OP3O	17	0	Op amp 3 output			
RING	35	I	Ringer drive input			
RINGON	36	Ι	Ringer enable (logic high to enable)			
TCOUT	41	0	Trickle-charge output			
VB	40	I	Battery voltage input for charging control			
Vcc	31		Power supply to most of the device			
VCH	20	ı	External power supply input for voltage detection			
VEXT	48	I	External voltage input			
VG1	46	0	MOSFET M1 gate drive			
VG2	38	0	MOSFET M2 gate drive			
VOUT1	26	0	LDO REG 1 output 1			
VOUT2	32	0	LDO REG 2 output 2			



Terminal Functions (Continued)

TERMINAL				
NAME	NO.	1/0	DESCRIPTION	
QI				
VOUT3	27	0	LDO REG 3 output 3	
VOUT4	29	0	LDO REG 4 output 4	
VOUT5	28	0	OO REG 5 output 5	
VOUT6	34	0	LDO REG 6 output 6	
VOUT7	44	0	LDO REG 7 output 7	
VREF	1	0	Voltage-reference bypass output	
VSUP	30	0	Power-supply switch output	

detailed description

battery-charging control

The battery charging control block in the device is a part of the lithium-ion battery (Li-Ion) charging system of the phone. It is capable of regulating the external power source to charge the lithium-ion battery according to the battery-charging requirements. More information on battery-charging control is presented in the *application information* section.

The MOSFET driver and its feedback-control circuit are enabled/disabled by a CMOS control signal provided by the phone's microprocessor. The maximum-charging current is set by external resistors for design flexibility.

overvoltage shutdown

The device shuts down the charging circuit in the presence of an overvoltage condition.

low-dropout linear voltage regulators

The device has seven separate low-dropout linear-voltage regulators. A single enable signal controls four of the regulators. The last three regulators are controlled by their own enable signals.

voltage detectors (with power-off delay)

The device has two voltage detectors. The voltage detectors monitor the voltage level of the external power and V_{CC} . The external power detector (VDET1) has a CMOS output. The V_{CC} detector (VDET2) activates on the falling edge and has user-adjustable power-off delay. There is an internal pullup resistor on the output.

analog multiplexer

The device has a four-channel analog multiplexer with two-bit channel-selector signal input and a shutdown function. In the shutdown mode, all the input and output terminals are in the high-impedance state.

operational amplifiers

The device has three rail-to-rail operational amplifiers with common shutdown control.

power supply switch for external phone accessories

The device provides current-limited voltage supply to the external phone accessories via the external-interface connector. The power supply switch is controlled by the same enable signal (EN1) that controls the four regulators—LDO1-LDO4. The external phone accessories are resistive in nature.

ringer driver

The device is capable of driving a ringer. It is controlled by a CMOS signal, and uses an N-channel low-side driver.



DISSIPATION-RATING TABLE - FREE-AIR TEMPERATURE

PACKAGE	T _A <25°C	OPERATING FACTOR	T _A = 70°C	T _A = 85°C
	POWER RATING	ABOVE T _A = 25°C	POWER RATING	POWER RATING
PFB	1962 mW	15.7 mW/°C	1256 mW	1020 mW

absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply-voltage range, V _{CC}	0.3 V to 6.5 V
External-voltage range	0.3 V to 15 V
Output-voltage range	–0.3 V to 6.5 V
Input-voltage range, all other pins	
Continuous total-power dissipation	See Dissipation-Rating Table
Free-air temperature range	–30°C to 85°C
Storage-temperature range	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Supply voltage Voc	In regulation	2.85	3.75	4.25	V	
Supply voltage, VCC	In transient condition	2.85		6	V	
VEXT	Allowable range	0	5.5	12	V	
VEXT	Normal charging operation	4.6	5.5	6	V	
VCH		2.1		6	V	
High-level logic input, VIH		2.1			V	
Low-level logic input, V _{IL}				0.9	V	

electrical characteristics over recommended operating junction temperature range, V_{CC} = 3.75 V and VEXT = 5.5 V (unless otherwise specified)

current table, $T_A = -40^{\circ}C$ to $85^{\circ}C$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Shutdown current	EN1 = EN2 = EN3 = EN4 = ENOP_MUX = VCH = CH = RINGON = VEXT = GND		50	90	
Quiescent current LDOreg. 1–4, power-switch quiescent current	EN1 = VOUT2, EN2 = EN3 = EN4 = ENOP_MUX = VCH = CH = RINGON = VEXT = GND		210	350	
Quiescent current LDOreg. 1–5, power-switch quiescent current	EN1 = EN2 = VOUT2, EN3 = EN4 = ENOP_MUX = VCH = CH = RINGON = VEXT = GND		240	400	
Quiescent current LDOreg. 1–6, power-switch quiescent current	EN1 = EN2 = EN3 = VOUT2, EN4 = ENOP_MUX = VCH = CH = RINGON = VEXT = GND		270	450	μΑ
Quiescent current LDOreg. 1–7, power-switch quiescent current	EN1 = EN2 = EN3 = EN4 = VOUT2, ENOP_MUX = VCH = CH = RINGON = VEXT = GND		300	500	
Quiescent current LDOreg. 1–7, Power-switch, MUX, op amp quiescent current	EN1 = EN2 = EN3 = EN4 = ENOP_MUX = VOUT2, VCH = CH = RINGON = VEXT = GND		470	800	
Quiescent current LDOreg. 1–4, Power-switch, MUX, op amp quiescent current	EN1 = ENOP_MUX = VOUT2, EN2 = EN3 = EN4 = RINGON = VCH = CH = VEXT = GND		370	700	
LDOreg. 1–7, Power-switch, MUX, op amp, charger quiescent current	VCH = 4.8 V, EN1 = EN2 = EN3 = EN4 = ENOP_MUX = CH = VOUT2, RINGON = GND		2.5	4.0	mA



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battery charging control, $T_A = 0$ °C to 50°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Constant voltage VB	Charge current = 50 mA, EN1 = CH = VOUT2, EN2 = EN3 = EN4 = ENOP_MUX = GND, VEXT = 5 - 6 V	4.15	4.20	4.25	V
	Voltage drop across sense resistor ICH+ - ICH-	CH = V _{CC}	85	100	115	mV
	Precharge current (VR6 threshold)	TCOUT – VB, VB <vtc< td=""><td>75</td><td>125</td><td>175</td><td>mV</td></vtc<>	75	125	175	mV
Vtc	Precharge threshold		3.30	3.40	3.50	V
lpc	Precharge capability	VB = 3.5 V, TCIN = 4.15 V, R6 =2 Ω , Current limit control is disabled	50			mA

over-voltage shutdown, $T_A = 0$ °C to 50°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vchco	Over-voltage cutoff point for VCH		4.7	5.4	6	V
Vgco	Over-voltage cutoff point for VEXT		6.5	7.5	8.5	V

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electrical characteristics over recommended operating junction temperature range, V_{CC} = 3.75 V and VEXT = 5.5 V (unless otherwise specified) (continued)

LDO regulator 1 (LCD Module), $T_A = -20^{\circ}C$ to $85^{\circ}C$

PARAMETER	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
Output voltage VOUT1	IOUT1 = 0.5 mA to 3 mA,	$V_{CC} = 3.3 \text{ V to } 4.2 \text{ V, EN1} = 3 \text{ V}$	2.95	3	3.05	V
Dropout voltage	IOUT1 = 1 mA				100	mV
Maximum current	V _{CC} = 3.75 V,	VOUT1 = 2.85 V	5			mA
Current limit	VOUT1 shorted to GND		7.5			mA
Ripple rejection	f = 400 Hz.	IOUT1 = 1 mA		50		dB

LDO regulator 2 (Digital), $T_A = -30^{\circ}C$ to $85^{\circ}C$

PARAMETER	TEST	TEST CONDITIONS		TYP	MAX	UNIT
Output voltage VOUT2	IOUT2 = 5 mA to 150 mA,	$V_{CC} = 3.3 \text{ V to } 4.2 \text{ V, EN1} = 3 \text{ V}$	2.825	3	3.175	V
Dropout voltage	IOUT2 = 80 mA				250	mV
Maximum current	V _{CC} = 3.75 V,	VOUT2 = 2.85 V	200			mA
Current limit	VOUT2 shorted to GND		300			mA
Ripple rejection	f = 400 Hz,	IOUT2 = 100 mA		50		dB

LDO regulator 3 (TCX0), $T_A = -30^{\circ}C$ to $85^{\circ}C$

PARAMETER	TES	TEST CONDITIONS			MAX	UNIT
Output voltage VOUT3	IOUT3 = 1 mA to 3 mA,	$V_{CC} = 3.3 \text{ V to } 4.2 \text{ V, EN1} = 3 \text{ V}$	2.825	3	3.175	V
Dropout voltage	IOUT3 = 3 mA				100	mV
Maximum current	V _{CC} = 3.75 V,	VOUT3 = 2.85 V	5			mA
Current limit	VOUT3 shorted to GND		7.5			mA
Ripple rejection	f = 400 Hz,	IOUT3 = 3 mA		60		dB

LDO regulator 4 (Audio), $T_A = -30^{\circ}C$ to $85^{\circ}C$

PARAMETER	TEST	TEST CONDITIONS		TYP	MAX	UNIT
Output voltage VOUT4	IOUT4 = 5 mA to 40 mA,	$V_{CC} = 3.3 \text{ V to } 4.2 \text{ V, EN1} = 3 \text{ V}$	2.825	3	3.175	V
Dropout voltage	IOUT4 = 40 mA				250	mV
Maximum current	$V_{CC} = 3.75 \text{ V},$	VOUT4 = 2.85 V	75			mA
Current limit	VOUT4 shorted to GND		112			mA
Ripple rejection	f = 400 Hz,	IOUT4 = 30 mA		60		dB

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electrical characteristics over recommended operating junction temperature range, V_{CC} = 3.75 V and VEXT = 5.5 V (unless otherwise specified) (continued)

LDO regulator 5 (RX), $T_A = -30^{\circ}C$ to $85^{\circ}C$

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Output voltage VOUT5	IOUT5 = 10 mA to 30 mA,	$V_{CC} = 3.3 \text{ V to } 4.2 \text{ V, EN1} = 3 \text{ V}$	2.825	3	3.175	V
Dropout voltage	IOUT5 = 20 mA				250	mV
Maximum current	V _{CC} = 3.75 V,	VOUT5 = 2.85 V	40			mA
Current limit	VOUT5 shorted to GND		60			mA
Ripple rejection	f = 400 Hz,	IOUT5 = 20 mA		60		dB

LDO regulator 6 (TX), $T_A = -30^{\circ}C$ to $85^{\circ}C$

PARAMETER	Т	TEST CONDITIONS		TYP	MAX	UNIT
Output voltage VOUT6	IOUT6 = 30 mA to 70	0 mA, $V_{CC} = 3.3 \text{ V to } 4.2 \text{ V, EN1} = 3 \text{ V}$	2.825	3	3.175	V
Dropout voltage	IOUT6 = 50 mA				250	mV
Maximum current	$V_{CC} = 3.75 \text{ V},$	VOUT6 = 2.85 V	70			mA
Current limit	VOUT6 shorted to GI	ND	105			mA
Ripple rejection	f = 400 Hz,	IOUT6 = 50 mA		60	·	dB

LDO regulator 7 (PLL), $T_A = -30^{\circ}C$ to $85^{\circ}C$

PARAMETER	TEST	TEST CONDITIONS		TYP	MAX	UNIT
Output voltage VOUT7	IOUT7 = 10 mA to 25 mA,	V _{CC} = 3.3 V to 4.2 V, EN1 = 3 V	2.825	3	3.175	V
Dropout voltage	IOUT7 = 20 mA				250	mV
Maximum current	V _{CC} = 3.75 V,	VOUT7 = 2.85 V	30			mA
Current limit	VOUT7 shorted to GND		45			mA
Ripple rejection	f = 400 Hz,	IOUT7 = 20 mA		60		dB
Output noise voltage (RMS)	BW = 300 Hz - 50 kHz	_			100‡	μV

[†] With external filtering

VDET1, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vсн	Threshold voltage of CH		2.85	3	3.15	V
	Hysteresis voltage of CH			100		mV
VODET1	Output voltage	VCH > THRESHOLDV		0	0.3	V
VODET2	Output voltage	VCH < THRESHOLDV		VOUT2	0.3	V
TCDET1	Temp. coefficient of VODET1			±100		ppm/°C



electrical characteristics over recommended operating junction temperature range, V_{CC} = 3.75 V and VEXT = 5.5 V (unless otherwise specified) (continued)

VDET2, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Threshold voltage of VCC		2.85	3	3.15	V
	Hysteresis voltage of VCC			100		mV
VODET1	Output voltage	VCH > THRESHOLDV		0	0.3	V
VODET2	Output voltage	VCH < THRESHOLDV		VOUT2		V
TCDET2	Temperature coefficient of VDET2			±100		ppm/°C
TDELAY2	Delay of VDET2	Cdet_delay = 0.1 μF	35	50	75	ms

power switch, $T_A = 25^{\circ}C$

	PARAMETER	TEST (CONDITIONS	MIN	TYP	MAX	UNIT
VSUP	Output voltage	ISUP = 0 mA - 50 mA	, V _{CC} = 3.75 V	3.45	3.60	3.75	V
VON	On voltage	$V_{CC} = 3.3 V - 5 V$,	ISUP = 30 mA			300	mV
I _{MAX}	Maximum current	V _{CC} = 3.75 V	,VSUP = 0 V			200	mA
IMIN	Minimum current	$V_{CC} = 3.75 \text{ V},$	VSUP = 3.45 V	70			mA

analog multiplexer, $T_A = -30^{\circ}C$ to $85^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Sine-wave distortion	1 kHz, 1 Vpp, 1.5 VDC offset		0.1%		
FMAX	Frequency response (switch on)	−3 dB gain	1			MHz
	Feed-through attenuation (switch off)	f = 250 kHz			-40	dB
	Crosstalk (control input to signal output)	Tr = Tf = 50 ns			100	mV
	Crosstalk (between switches)	f = 250 kHz			-50	dB
DC CH	ARACTERISTICS					
RON	On resistance			700	1200	Ω
ΔRON	Difference of ON resistance between switches			10		Ω
loff	Input/output leakage current				±400	nA
IZ	Switch input leakage current				±400	nA
I _{IN}	Control-input current				±1	μΑ
Iq	Quiescent current				10	μΑ
AC CH	ARACTERISTICS					
	Phase difference between input and output	1 kHz (spec is flexible, dependent on the design)			50	ns
	Output enable time tpzl, tpzh				100	ns
	Output disable time tplz, tphz				150	ns
C _{IN}	Control input capacitance	All pins			10	pF
C _{IOS}	Input terminal capacitance				15	pF
C _{IS}	Output terminal capacitance				50	pF
C _{IOS}	Feed-through capacitance				2	pF

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electrical characteristics over recommended operating junction temperature range, V_{CC} = 3.75 V and VEXT = 5.5 V (unless otherwise specified) (continued)

operational amplifiers, $T_A = -30^{\circ}C$ to $85^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vos	Input offset voltage	Vcm = 1.5 V		2	10	mV
IOPB	Input bias current			50	250	na
lopos	Input offset current			5	50	nA
R _{IN}	Input resistance	DC resistance		100		МΩ
CMMR	Common-mode rejection ratio	f = 400 Hz, Vcm = 1.5 V	65	75		dB
VCM	Input common voltage		0.1		2.9	V
PSRR	Power-supply rejection ratio	f = 400 Hz, Vcm = 1.5 V	60	70		dB
C _{IN}	Common-mode input capacitance			3		pF
V-	Output swing, high	Output high, I _O = 2.5 mA (source)	2.9	2.95		V
VO	Output swing, low	Output low, $I_O = -2.5 \text{ mA (sink)}$		0.1	0.15	V
lo	Output current	DC Current			±2.5	mA
THD	Total harmonic distortion	f = 1 kHz, 20 dB closed-loop gain, I _O = 0.5 mA		1%		
SR	Slew rate			0.3†		V/µs
GBW	Gain bandwidth product			300		kHz

ringer driver, $T_A = -30^{\circ}C$ to $85^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
RON	On resistance	RINGON = V_{CC} , IOUTRING = 100 mA, $T_A = 25^{\circ}C$			3	Ω
TONRING	Turnon time				10	μs
TOFFRING	Turnoff time				10	μs

internal power supply

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VINTERNAL	Output voltage	ILOAD = 7.5 mA	3.1	3.25	3.4	V

bandgap reference

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Output voltage		1.1812	1.192	1.2028	V
	Output noise voltage (RMS)	BW = 300 Hz – 50 kHz			800	nV/Hz
REFVALID	Reference valid			5		μΑ

thermal shutdown

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Trip point		160		190	°C
Hysteresis temperature			15		°C

THERMAL INFORMATION

The implementation of integrated circuits in low-profile and fine-pitch surface-mount packages requires special attention to power dissipation. Many system-dependent issues such as thermal coupling, airflow, added heat sinks and convection surfaces, and the presence of other heat-generating components affect the power-dissipation limits of a given component.

Three basic approaches for enhancing thermal performance are listed below.

- Improving the power dissipation capability of the printed-circuit board design
- Improving the thermal coupling of the component to the printed-circuit board
- Introducing airflow into the system

Using the given R_{0,JA} for this device, the maximum power dissipation can be calculated with the equation:

$$P_{D(MAX)} = \frac{T_{J(MAX)} - T_A}{R_{\theta, IA}}$$

APPLICATION INFORMATION

capacitor selection

The output bypass capacitor of each LDO regulator should be selected from the list of ceramic capacitors shown below. The VCC bypass capacitors should be selected from the list of tantalum capacitors shown below. Tantalum capacitors have good temperature stability and offer good capacitance for their size. Care should be taken when using marginal quality tantalum capacitors, as the increase of the equivalent series resistance (ESR) at low temperatures can cause instability. For a given capacitance, ceramic capacitors are usually larger and more costly than tantalums. The capacitance of ceramic capacitors varies greatly with temperature. In addition, the ESR of ceramic capacitors can be low enough to cause instability. A low-value resistor can be added in series with the ceramic capacitor to provide a minimum ESR.

ceramic (X7R or X5R)

CAPACITANCE	CASE SIZE	ESR (MAX)
1 μF	0805	$3.8~\text{m}\Omega$
2.2 μF	0805	$4.5~\text{m}\Omega$
3.3 μF	0805	$4.1~\text{m}\Omega$
2.2 μF	1206	$3.4~\text{m}\Omega$
4.7 μF	1206	1.9 mΩ

tantalum (6.3 V rating)

CAPACITANCE	CASE SIZE	ESR (MAX)
4.7 μF	A(3216)	6 Ω
6.8 μF	A(3216)	6 Ω
10 μF	A(3216)	4 Ω
10 μF	P(0805)	6 Ω



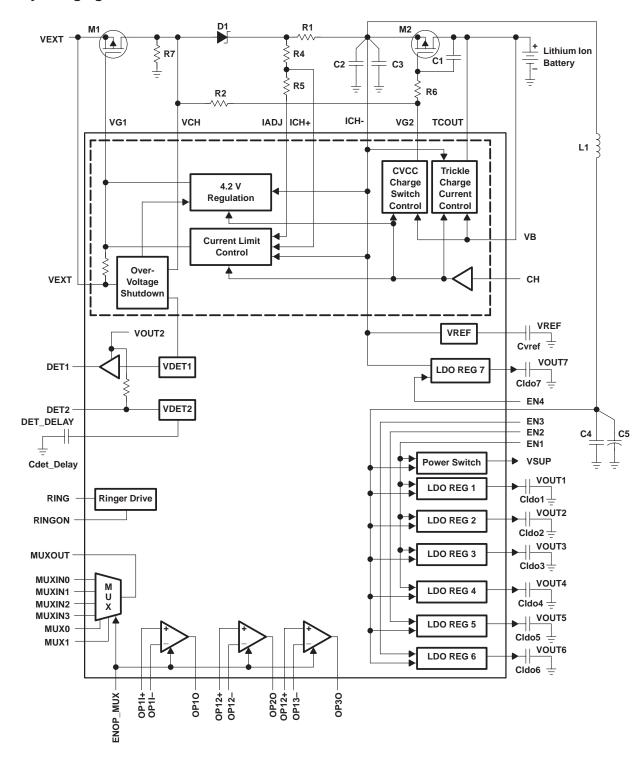
APPLICATION INFORMATION

recommended parts list

REFERENCE	DESCRIPTION	MANUFACTURER	VALUE	PART NUMBER
C1	Ceramic, 0805, X7R		100 pF	
C2	Ceramic, 0805, X7R		0.01 μF	
C3	Tantalum, 6.3 V, Case B, 20%	Siemens Matsushita	10 μF	B 45 196-E1106-M20
C4	Ceramic, 0805		0.01 μF	
C5	Tantalum, 6.3 V, Case B, 20%	Siemens Matsushita	10 μF	B 45 196-E1106-M20
Cldo1	Ceramic, 0805, X7R		0.22 μF	
Cldo2	Ceramic, 10 V, 1206, X5R, 20%	Taiyo Yuden	4.7 μF	LMK316BJ475ML
Cldo3	Ceramic, 0805, X7R		0.22 μF	
Cldo4	Ceramic, 10 V, 1206, X5R, 20%	Taiyo Yuden	3.3 μF	LMK316BJ335ML
Cldo5	Ceramic, 16 V, 0805, X5R, 20%	Taiyo Yuden	2.2 μF	LMK212BJ225MG
Cldo6	Ceramic, 10 V, 1206, X5R, 20%	Taiyo Yuden	4.7 μF	LMK316BJ475ML
Cldo7	Ceramic, 16 V, 0805, X5R, 20%	Taiyo Yuden	2.2 μF	LMK212BJ225MG
Cvref	Ceramic, 0805, X7R		1000 pF	
Cdet_delay	Ceramic, 0805, X7R		0.1 μF	
D1	Schottky diode	Rohm		RB051L-40
L1			1 μΗ	
M1		Siliconix		Si3455DV
		Fairchild		FDC654P
M2		Siliconix		Si3441DV
		Siliconix		Si3443DV
		Siliconix		Si2305DS
		Fairchild		FDC634P
R1	1/4 W, 5%		0.1 Ω	
R2	0805, 1/10 W, 5%		10 kΩ	
R3	0805, 1/10 W, 5%		1 kΩ	
R4	0805, 1/10 W, 5%		560 Ω	
R5	0805, 1/10 W, 5%		6.8 kΩ	
R6	0805, 1/10 W, 5%		2.7 Ω	
R7	0805, 1/10 W, 5%		10 kΩ	

APPLICATION INFORMATION

battery charging control



APPLICATION INFORMATION

battery-charging control (continued)

The battery-charging control block in the device is a part of the Li-lon battery charging system of the phone. The device controls the P-channel MOSFET to accomplish constant-voltage/constant-current charging (CVCC) within a $\pm 1\%$ tolerance in the charging termination voltage.

The battery charging control consists of the two sections:

- CVCC charge-switch control with feedback loops for voltage and current control
- Trickle charge-current control

When the voltage-detector output (DET1) is set high, the voltage-control loop is activated to regulate the voltage of ICH- to 4.2 V. Then, when the control signal input CH is set high, either the current-control loop or the trickle-charge control block is activated, depending upon battery voltage.

When VB is below the threshold Vtc, the trickle-charge current control block directs the current to the battery via TCIN, trickle-charging current control, TCOUT, R6, and the battery. The measure of the voltage across sense resistor R6 is used for feedback-control of the rate of charging current.

Once the battery voltage reaches the threshold Vtc, the CVCC charge-switch control block becomes active and controls the P-channel MOSFET M1. The feedback control ensures that the voltage ICH- does not exceed 4.2 V ± 0.05 V (4.2 V regulation), and the current draw of resistor R1 does not exceed the specified value (current-limit control). In this case, the charging current drains via R1, M2, and the battery. The maximum charging current is set by external resistors for design flexibility.

analog multiplexer output table

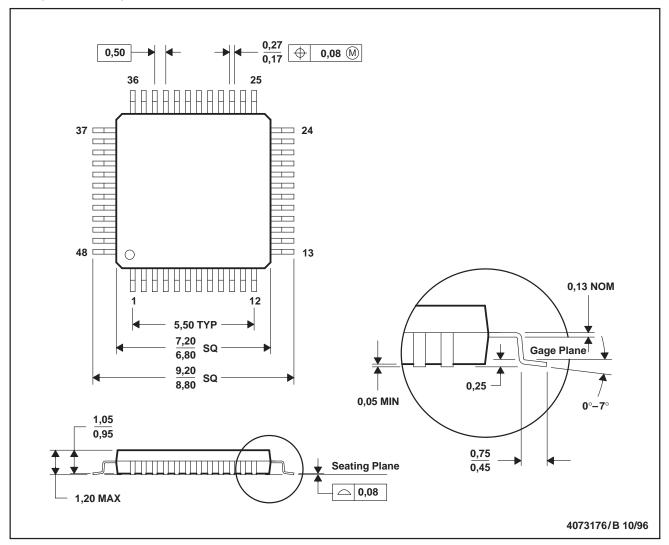
MUX1	MUX2	OUTPUT
0	0	MUXIN0
0	1	MUXIN1
1	0	MUXIN2
1	1	MUXIN3



MECHANICAL DATA

PFB (S-PQFP-G48)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-026

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